

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/644,158	TOUTOUCHI ET AL.	
Examiner		Art Unit		Page 1 of 2
Stacy A. Whitmore		2825		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,732,309	05-2004	Toutouchi et al.	714/725
	B	US-6,687,883	02-2004	Cohn et al.	716/4
	C	US-6,678,645	01-2004	Rajsuman et al.	703/20
	D	US-6,532,440	03-2003	Boppana et al.	703/14
	E	US-6,449,751	09-2002	Hussain et al.	716/4
	F	US-6,029,117	02-2000	Devgan, Anirudh	702/58
	G	US-5,515,302	05-1996	Horr et al.	358/1.15
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Chakravarty, S., et al., "IDQ measurement based diagnosis of bridging faults in full scan circuits", Febraru, 1993. Department of Computer Science, State University of New York at Buffalo, Technical Report No: 93-04. pgs. 1-12
	V	Rajsuman, R., "IDQ testing for CMOS VLSI", 4/2000. IEEE, pgs. 544-568.
	W	Rajsuman, R., "Design-for-IDQ-testing for embedded cores based system-on-a-chip", 11/1998. IEEE, pgs. 69-73.
	X	Chakravarty, S. et al., "Algorithms for current monitor based diagnosis of bridging and leakage faults", ACM/IEEE Design Automation Conference, pgs. 353-356.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/644,158	TOUTOUCHI ET AL.	
Examiner		Art Unit		Page 2 of 2
Stacy A. Whitmore		2825		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Isern, E., et al., "IDDQ test and diagnosis of CMOS circuits". 1995. IEEE. pgs. 60-67.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.